

Model: XD-200

Analytical Probe Station

>> The Probe Station XD-200

is a dedicated probing solution that comes with everything you need to achieve accurate measurement results in the shortest time, with maximum confidence. The system Provides best known methods for I-V/C-V measurements.

Designed for upgradability and extendable with multiple options. The Probe Station XD-200 can be easily reconfigured to meet your future project requirements, such as high voltage testing.

>> Specifications

Vacuum Chuck 8"
Huged-Knob Chuck Stage
Chuck stage 8"×8" Travel
Chuck Theta 0°~30°
Microscope Stage 2"×2" Travel
Platen Up/Down 6mm Adjustable/Coarse Adjustment/Lever-Driven
Platen Up/Down 25mm Adjustable/Fine Adjustment/Hand wheel-Driven
660mmW x 660mmD x 700mmH With Microscope
Weight 80kg with microscope



>> Accessories

Microscope Magnification : 1000X
Hot Chuck : 200/300/400°C
Special Chuck Design for RF
Chuck Up/Down 4mm Adjustable
CCD and Screen
Micropositioner
Tip Holder
Shielding Box
Vibration Free Table